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PATENT NUMBER

U.S. UTILITY PATENT APPLICATION

J.S. UT	ILITY PATI	ENT API	LICATION
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CONT/PRIOR Hollington APPLICATION NO. 09/973049 2829 Kazunobu Miki Semiconductor element test apparatus, and method of testing semiconductor element using the apparatus

	ISSUING C	CROSS REFERENCE(8)
ORIGINAL		SUBCLASS (ONE SUBCLASS PER BLOCK)
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STERNATIONAL CLASSIFICATION		
TERMATIONAL SECTION	Later T	為多利以於世界的計劃的一個
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TERMINAL	DRAWINGS	CLAIMS ALLOWED
	Sheets Drwg. Figs. Drwg. Print Fig.	Total Claims Print Claim for O.G.
		NOTICE OF ALLOWANCE MAILED
a) The term of this patent subsequent to (date) has been disclaimed.	(Assistant Examiner) (Date)	
b) The term of this patent shall not extend beyond the expiration date		ISSUE FEE
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